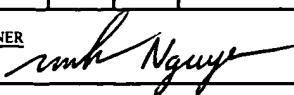


| Form PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF ART CITED BY APPLICANT (Use several sheets if necessary) | | | | | ATTY. DOCKET NO. MI22-16804 | PRIORITY SERIAL NO. 09/137,629 | |
|--|----|---|----------|-----------------------------------|---|-----------------------------------|----------------------------|
| | | | | | APPLICANT David R. Hembree | | |
| | | | | | PRIORITY FILING DATE August 21, 1998 | PRIORITY GROUP 2858 | |
| U.S. PATENT DOCUMENTS | | | | | | | |
| *Examiner Initial | | Document Number | Date | Name | Class | Subclass | Filing Date If Appropriate |
| VN | AA | 4,560,216 | 12/24/85 | Egawa | | | |
| | AB | 4,754,555 | 7/5/88 | Stillman | | | |
| | AC | 5,475,317 | 12/12/95 | Smith | | | |
| | AD | 5,495,667 | 3/5/96 | Farnworth et al. | | | |
| OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.) | | | | | | | |
| | AE | S/N 09/032,184; Filed 2/27/98; Akram et al.; Amendment filed 12/10/00; CPA filed 7/28/00; Amendment filed 3/3/00; Amendment filed 8/23/00; | | | | | |
| | | Original Application filed 2/27/98; Pending Claims. | | | | | |
| VN | AF | Advertisement for Probe Technology; www.idinet.com ; Interconnect Devices, Inc., 1 page; 3/6/98 | | | | | |
| | | | | | | | |
| VN | AG | Good Things Come In Small BGA/CSP Packages; www.johnstech.com/4/handbook/page9.html ; 1 page; 3/5/98 | | | | | |
| | | | | | | | |
| VN | AH | Product Description for Double Ended Probes, B1052 Series; www.testprobe.com/products/b1052.html ; Rika Densi America, Inc.; 1 page; 2/4/98. | | | | | |
| | | | | | | | |
| VN | AI | Product Description for Test Centers, RM-500 Series Probes, www.testprobe.com/products/rm500.html ; Rika Densi America, Inc.; 1 page; 2/4/98. | | | | | |
| | | | | | | | |
| VN | AJ | Product Description for Cost Effective Interconnections for High I/O Products; www.testprobe.com/products/io.htm#b1303 ; Rika Densi America, Inc.; | | | | | |
| | | 1 page; 2/4/98. | | | | | |
| VN | AK | Product Description for Ball Grid Probe B1303-C3; www.testprobe.com/products/io.htm#b1303 ; Rika Densi America, Inc.; 1 page; 2/4/98. | | | | | |
| | | | | | | | |
| VN | AL | Product Description for Test Socket Contacts; www.johnstech.com/4/handbook/page9.html ; 1 page; 3/5/98 | | | | | |
| | | | | | | | |
| EXAMINER <i>mh Nguyen</i> | | | | DATE CONSIDERED <i>03/22/2002</i> | | | |

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|--|-----------------|------------|-----------|--|---------------|-------------------------------|--------------------------|
| | | | | APPLICANT Micron Technology, Inc. | | | |
| | | | | FILING DATE April 4, 2001 | GROUP 2858 | | |
| U.S. PATENT DOCUMENTS | | | | | | | |
| *Examiner Initial | Document Number | Date | Name | Class | Subclass | Filing Date If Appropriate | |
| <u>VN</u> | AA 6,004,471 | 12/21/1999 | Chuang | | | | |
| <u>VN</u> | AB 5,550,526 | 8/27/1996 | Mottahead | | | | |
| | AC | | | | | | |
| | AD | | | | | | |
| OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.) | | | | | | | |
| | AE | | | | | | |
| | AF | | | | | | |
| | AG | | | | | | |
| | AH | | | | | | |
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| | AJ | | | | | | |
| | AK | | | | | | |
| | AL | | | | | | |
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| | | | | FILING DATE April 4, 2001 | | GROUP 2858 | | |
| U.S. PATENT DOCUMENTS | | | | | | | | |
| *Examiner Initial | | Document Number | Date | Name | | Class | Subclass | Filing Date If Appropriate |
| /N | AA | 5,378,311 | 1/3/95 | Nagayama et al. | | | | |
| | AB | | | | | | | |
| | AC | | | | | | | |
| | AD | | | | | | | |
| OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.) | | | | | | | | |
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| <u>EXAMINER</u> <u>muh Nguyen</u> | | | | <u>DATE CONSIDERED</u> <u>03/22/2002</u> | | | | |
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